

Notice of References Cited	Application/Control No. 10/824,569	Applicant(s)/Patent Under Reexamination KAPLAN, TODD	
	Examiner Linh V. Nguyen	Art Unit 2819	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0105449 A1	08-2002	Schreier et al.	341/139
*	B	US-6,348,884 B1	02-2002	Steensgaard-Madsen, Jesper	341/118
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
	Q					
	R					
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NON-PATENT DOCUMENTS

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